


<b>Search Notes</b>  	<b>Application/Control No.</b>  10840110	<b>Applicant(s)/Patent Under Reexamination</b>  WEEL, MARTIN
	<b>Examiner</b>  Oanh Duong	<b>Art Unit</b>  2441

SEARCHED			
Class	Subclass	Date	Examiner
709	203, 217, 219, 231, 232	7/5/2011	o.d
707	999.01	7/5/2011	p.d

SEARCH NOTES		
Search Notes	Date	Examiner
EAST text search of USPAT, JPO, EPO, DERWENT, IBM_TDB, US-PGPUB	7/5/2011	O.D
Inventor name & assigned search conducted	7/5/2011	o.d

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
US-PGPUB, USPAT, UPAD	see interference search history	7/5/2011	o.d

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